









RF Exposure Evaluation Report

Product	:	Wireless dynamic multi-parameter holter	
Trade mark	:	N/A	
Model/Type reference	:	M5,M12,Lepod,Lepod Pro,LMT-5,LMT-12	
Test Model No.	1	M12	
Serial Number	X	N/A	
Report Number	:	EED32O80211002	
FCC ID	:	2ADXK-8100	
Date of Issue	:	Mar. 30, 2022	
	:	47 CFR Part 1.1307	
Test Standards		47 CFR Part 2.1093	
Test Standards		KDB447498D04 Interim General RF	
		Exposure Guidance	
Test result	4	PASS	

Prepared for:

Shenzhen Viatom Technology Co., Ltd. 4E, Building 3, Tingwei Industrial Park, No.6 Liufang Road, Block 67,Xin'an Street, Baoan District, Shenzhen, 518101, Guangdong, China

> Prepared by: Centre Testing International Group Co., Ltd. Hongwei Industrial Zone, Bao'an 70 District, Shenzhen, Guangdong, China TEL: +86-755-3368 3668 FAX: +86-755-3368 3385

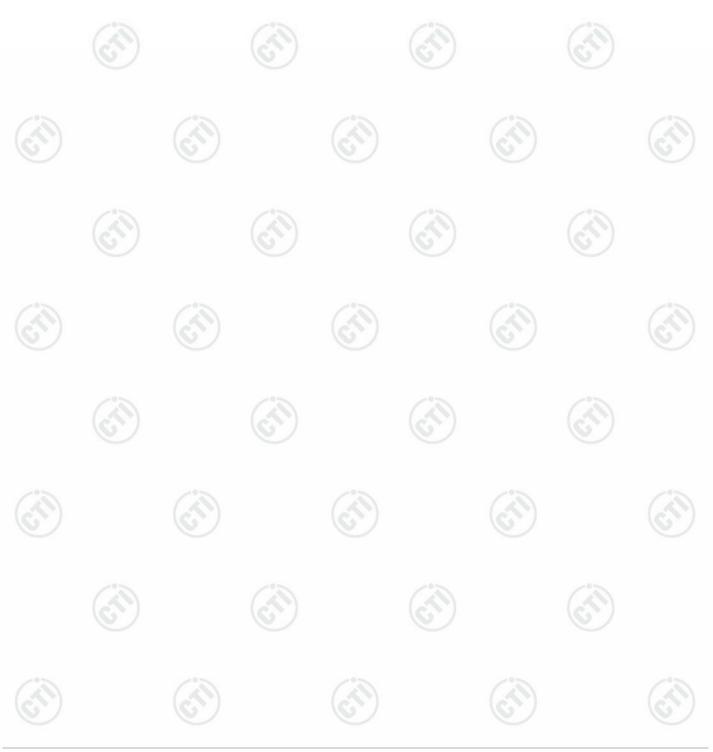
Compiled by:	Jirazer. Li	Reviewed by:	Lavon Ma
Approved by:	David Wang	Date:	Mar. 30, 2022
	David Wang		Check No.: 4753210222
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1 Version

Version No.	Date	Description				
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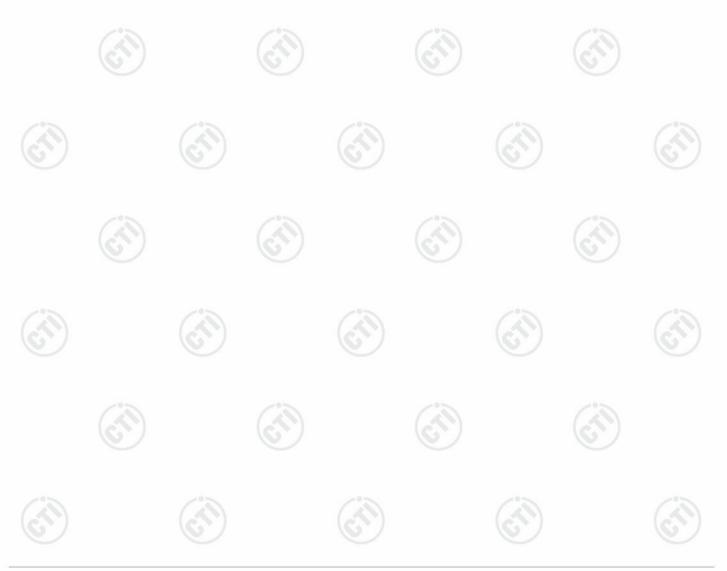
CTI华测检测

Report No.: EED32O80211002

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General Information 3

3.1 Client Information

Applicant:	Shenzhen Viatom Technology Co., Ltd.
Address of Applicant:	4E, Building 3, Tingwei Industrial Park, No.6 Liufang Road, Block 67,Xin'an Street, Baoan District, Shenzhen, 518101, Guangdong, China
Manufacturer:	Shenzhen Viatom Technology Co., Ltd.
Address of Manufacturer:	4E, Building 3, Tingwei Industrial Park, No.6 Liufang Road, Block 67,Xin'an Street, Baoan District, Shenzhen, 518101, Guangdong, China
Factory:	Shenzhen Viatom Technology Co., Ltd.
Address of Factory:	4E, Building 3, Tingwei Industrial Park, No.6 Liufang Road, Block 67,Xin'an Street, Baoan District, Shenzhen, 518101, Guangdong, China

3.2 General Description of EUT

Product Name:	Wireless dynamic multi-parameter holter	
Mode No.:	M5,M12,Lepod,Lepod Pro,LMT-5,LMT-12	13
Test Mode No.:	M12	(\mathcal{L})
Trade mark:	N/A	J
EUT Supports Radios application:	Bluetooth 5.1 dual mode: 2402-2480MHz	
Bluetooth Version:	V5.1	
Product Type:	Mobile Portable Fix Location	
Power Supply:	Battery: DC 3.8V,1.52Wh,400mAh	
Test Voltage:	DC 3.8V	
Sample Received Date:	Mar . 22, 2022	13
Sample tested Date:	Mar . 28, 2022 to Mar. 29, 2022	(\mathcal{A})
Remark:		J

Company Name and Address shown on Report, the sample(s) and sample Information was/ were provided by the applicant who should be responsible for the authenticity which CTI hasn't verified.

Model No.: M5,M12,Lepod,Lepod Pro,LMT-5,LMT-12

Only the model M12 was tested, since the electrical circuit design, layout, components used and internal wiring were identical for the above models, with difference being shell color and whether or not a core conductance cable is available.

3.3 General Description of BLE

Operation Frequency:	2402MHz~2480MHz			
Modulation Type:	GFSK			
Transfer Rate:	1Mbps 2Mbps	(1)	13	
Number of Channel:	40	(\sim)	(5))
Antenna Type:	Internal Antenna	U	C	
Antenna Gain:	3.45 dBi			

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3.4 Test Location

All tests were performed at:

Centre Testing International Group Co., Ltd Building C, Hongwei Industrial Park Block 70, Bao'an District, Shenzhen, China Telephone: +86 (0) 755 33683668 Fax:+86 (0) 755 33683385

No tests were sub-contracted.

FCC Designation No.: CN1164

3.5 Deviation from Standards

None.

3.6 Abnormalities from Standard Conditions

None.

3.7 Other Information Requested by the Customer

None.









4 SAR Evaluation

4.1 RF Exposure Compliance Requirement

4.1.1 Standard Requirement

According to KDB447498D04 Interim General RF Exposure Guidance Standalone SAR test exclusion considerations

Unless specifically required by the published RF exposure KDB procedures, standalone 1-g head or body

and 10-g extremity SAR evaluation for general population exposure conditions, by measurement or numerical simulation, is not required when the corresponding SAR Exclusion Threshold condition, listed

below, is satisfied.

Limits

The 1-g and 10-g SAR test exclusion thresholds for 100 MHz to 6 GHz at test separation distances \leq 50 mm are determined by:

[(max. power of channel, including tune-up tolerance, mW)/(min. test separation distance, mm)] · $[\sqrt{f}(GHz)] \le 3.0$ for 1-g SAR and ≤ 7.5 for 10-g extremity SAR, where

f(GHz) is the RF channel transmit frequency in GHz

Power and distance are rounded to the nearest mW and mm before calculation¹⁷

The result is rounded to one decimal place for comparison

The test exclusions are applicable only when the minimum test separation distance is \leq 50 mm and for transmission frequencies between 100 MHz and 6 GHz. When the minimum test separation distance is < 5 mm, a distance of 5 mm is applied to determine SAR test exclusion







Hotline:400-6788-333







4.1.2 EUT RF Exposure

1) For BLE 1Mbps

Measurement Data

GFSK mode 1Mbps					
Peak Output Power	Tune up tolerance	Maximum tune-up Power			
(dBm)	(dBm)	(dBm)	(mW)		
-0.31	-1.0±1	0	1.000		
-0.19	-1.0±1	0	1.000		
-0.55	-1.0±1	0	1.000		
	Peak Output Power (dBm) -0.31 -0.19	Peak Output Power (dBm)Tune up tolerance (dBm)-0.31-1.0±1-0.19-1.0±1	Peak Output Power (dBm)Tune up tolerance (dBm)Maximum tur (dBm)-0.31-1.0±10-0.19-1.0±10		

2) For BLE 2Mbps

Measurement Data

GFSK mode 2Mbps					
Test channel	Peak Output Power	Tune up tolerance	Maximum tune-up Power		
	(dBm)	(dBm)	(dBm)	(mW)	
Lowest(2402MHz)	-0.38	-1.0±1	0	1.000	
Middle(2440MHz)	-0.25	-1.0±1	0	1.000	
Highest(2480MHz)	-0.60	-1.0±1	0	1.000	

Channel		Maximum Peak Conducted el tolerance		Maximum tune- up Power		Calculated	Exclusion
	Output Power (dBm)	(dBm)	(dBm)	(mW)	value	threshold	
	owest 02MHz)	-0.31	-1.0±1	0	1.000	0.310	3
	1iddle 40MHz)	-0.19	-1.0±1	0	1.000	0.312	3.0
2 1	ighest 80MHz)	-0.55	-1.0±1	0	1.000	0.315	Ć

Remark: The Max Conducted Peak Output Power data refer to report Report No.: EED32080211001.



















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PHOTOGRAPHS OF EUT Constructional Details

Refer to Report No. EED32O80211001 for EUT external and internal photos.

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